## Notice of References Cited Application/Control No. 10/657,206 Examiner Alex Liew Applicant(s)/Patent Under Reexamination LIM ET AL. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0161151	08-2004	Iwayama et al.	382/187
*	В	US-3,701,972	10-1972	Arnold D. Berkeley; et. al.	710/36
*	С	US-4,180,798	12-1979	Komori et al.	382/181
*	D	US-6,705,872	03-2004	Pearson et al.	434/322
*	Ε	US-4,799,077	01-1989	Kaplan et al.	396/105
*	F	US-2004/0120598	06-2004	Feng, Xiao-Fan	382/263
*	G	US-2002/0165803	11-2002	lwase et al.	705/28
	Н	US-			
	-	US-			
	J	US-		·	
	κ	US-			·
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т	·				

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	v	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.